

Notice of References Cited

Application/Control No.

10/046,622

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

SHAIENDRA - KUMAR

Art Unit

1621

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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